JJMICROELECTRONICS

100V, 57A, 17.6mΩ N-channel Power SGT MOSFET

JMSL1018PGQ

Features

- Ultra-low ON-resistance, RDS(ON)
- Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant
- AEC-Q101 Qualified

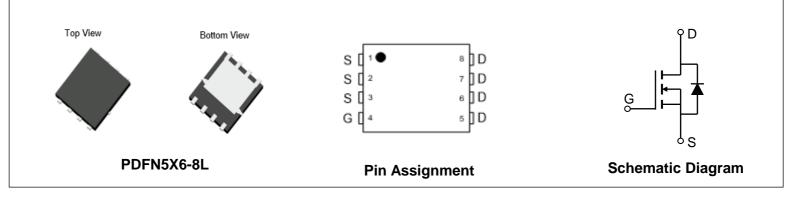
Applications

- Load Switch
- PWM Application
- General Automtoive Application

Product Summary

Parameters	Value	Unit
V _{DSS}	100	V
V _{GS(th)_Typ}	1.5	V
I _D (@V _{GS} =10V)	57	А
R _{DS(ON)_Typ} (@V _{GS} =10V	13.2	mΩ
R _{DS(ON)_Typ} (@V _{GS} =4.5V	17.6	mΩ





Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSL1018PGQ-13	L1018PQ	1	Tape&Reel	PDFN5x6-8L	5000	50000

Absolute Maximum Ratings (@ $T_c = 25^{\circ}C$ unless otherwise specified)

Symbol	Parameter		Value	Unit	
V _{DS}	Drain-to-Source Voltage		100	V	
V _{GS}	Gate-to-Source Voltage		±20	V	
	Continuous Drain Current	$T_C = 25^{\circ}C$	57	А	
ID	Continuous Drain Current	$T_{\rm C} = 100^{\circ}{\rm C}$	41	A	
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	A	
E _{AS}	Single Pulsed Avalanche Energy ⁽²⁾		44	mJ	
PD	Rower Discinction	$T_C = 25^{\circ}C$	105	W	
'D	Power Dissipation	$T_{\rm C} = 100^{\circ}{\rm C}$	52		
T _J , T _{STG}	Junction & Storage Temperature Range		-55 to 175	°C	

Thermal Characteristics

Symbol	Parameter	Мах	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	46	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	C/VV

				-		
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0V$	100	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	1.0	μA
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, \ I_D = 250 \mu A$	1.1	1.5	2.0	V
D		$V_{GS} = 10V, I_D = 20A$	-	13.2	17.1	mΩ
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 4.5 V, I_{D} = 15 A$	-	17.6	22.9	mΩ
Dynami	c Characteristics				-	
R_g	Gate Resistance	f = 1MHz	-	1.6	-	Ω
C _{iss}	Input Capacitance		725	1015	1370	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 50V,$ f = 1MHz	254	356	480	pF
C _{rss}	Reverse Transfer Capacitance		13	19	25	pF
Qg	Total Gate Charge		13	18	24	nC
Q _{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 50V, I_D = 20A$	3	4	5	nC
Q_gd	Gate Drain("Miller") Charge	$v_{\rm DS} = 50 v, v_{\rm D} = 20 A$	3	4	6	nC
				•	·	
	ng Characteristics			1		
t _{d(on)}	Turn-On DelayTime	4	-	7	-	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 50V$	-	18	-	ns
t _{d(off)}	Turn-Off DelayTime	$I_D = 20A, R_{GEN} = 3\Omega$	-	19	-	ns
t _f	Turn-Off Fall Time		-	5	-	ns
Body D	iode Characteristics			1	I	r.
I _S	Maximum Continuous Body Diode Forward Current		-	-	57	А
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	230	А
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	I _F = 15A, di/dt = 100A/us	23	33	44	ns
Qrr	Body Diode Reverse Recovery Charge	$T_{\rm F} = 10$ A, u/ut = 100 A/us	-	29	-	nC

Electrical Characteristics ($T_J = 25^{\circ}C$ unless otherwise specified)

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

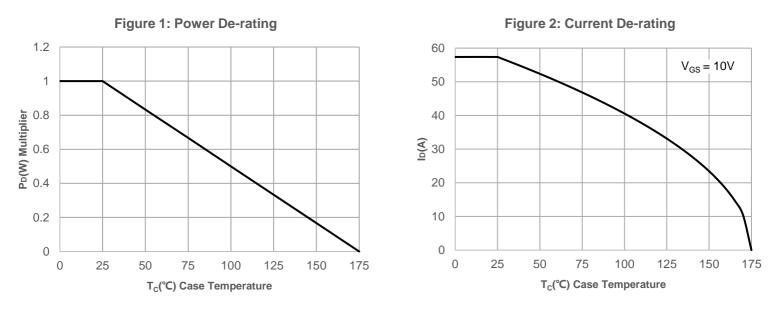
2. E_{AS} condition: Starting T_J =25C, V_{DD} =50V, V_G =10V, R_G =25ohm, L=0.5mH, I_{AS} =13.3A, V_{DD} =0V during time in avalanche.

3. $R_{\theta JA}$ is measured with the device mounted on a 1inch 2 pad of 2oz copper FR4 PCB.

4. Pulse Test: Pulse Width ${\leqslant}300\mu s,$ Duty Cycle ${\leqslant}0.5\%.$

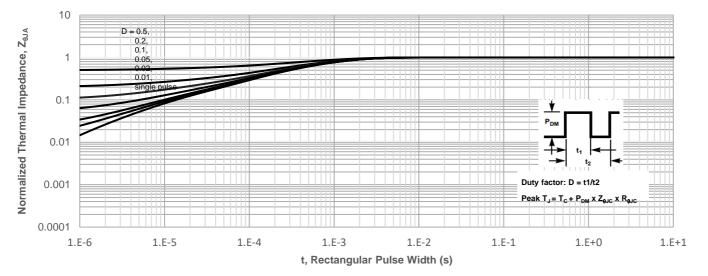




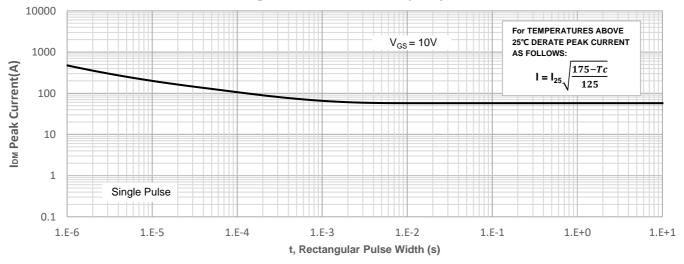


Typical Performance Characteristics













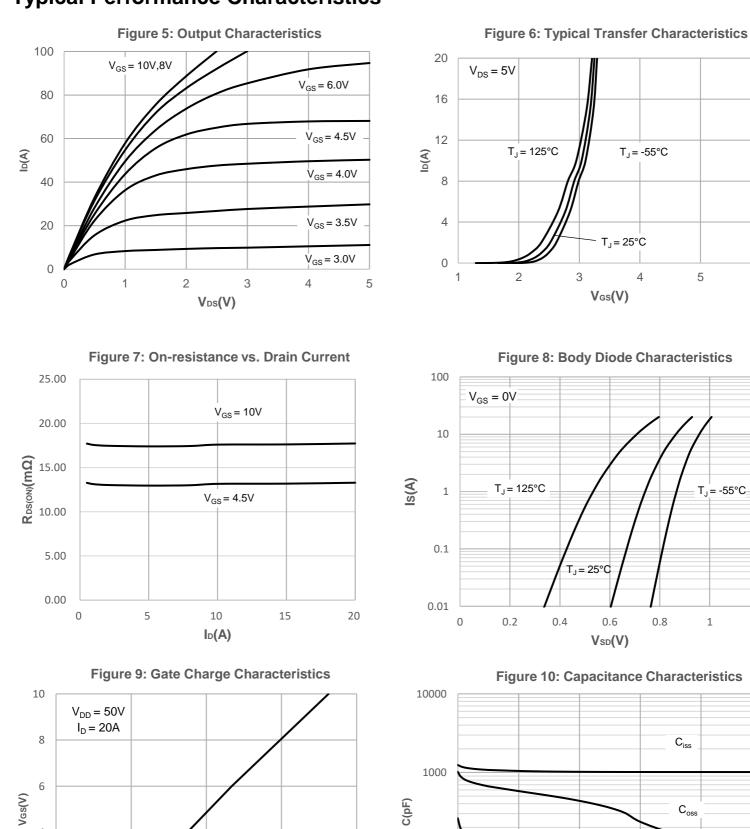
4

2

0

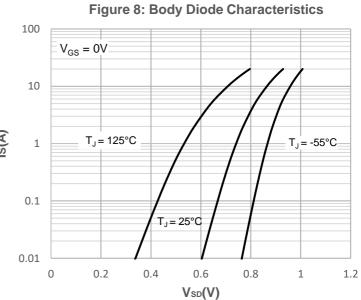
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5

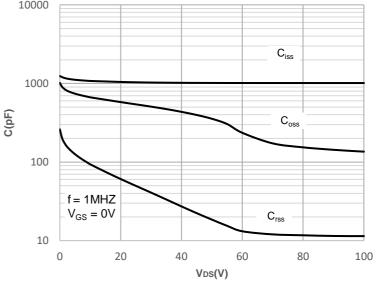


Typical Performance Characteristics

 $T_J = -55^{\circ}C$ T_J = 25°C 3 4 5 6 Vgs(V)







10

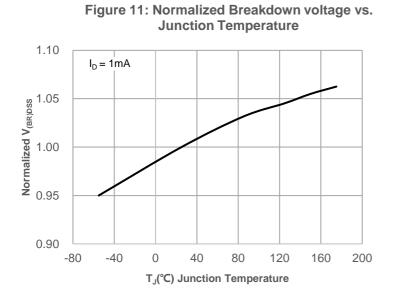
Qg(nC)

15

20



Typical Performance Characteristics





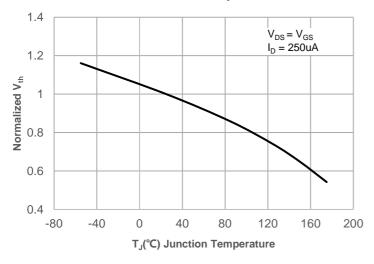
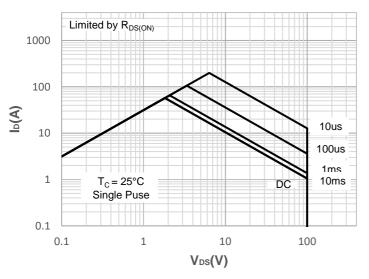
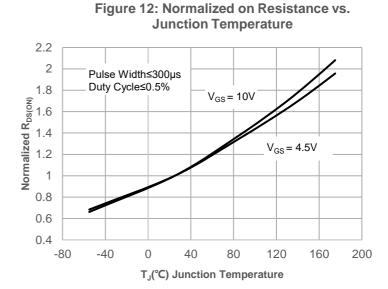
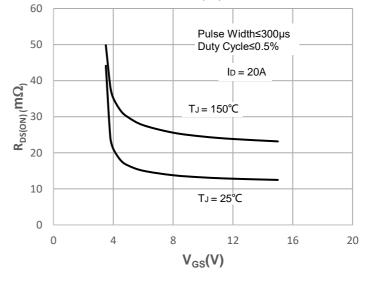


Figure 15: Maximum Safe Operating Area











Test Circuit

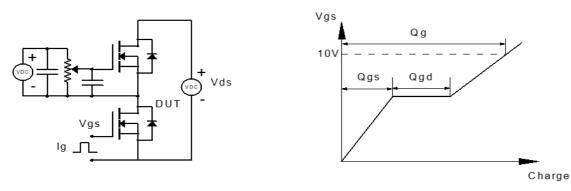


Figure 1: Gate Charge Test Circuit & Waveform

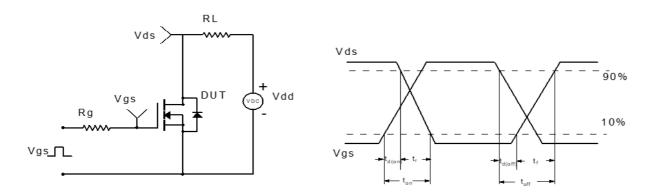


Figure 2: Resistive Switching Test Circuit & Waveform

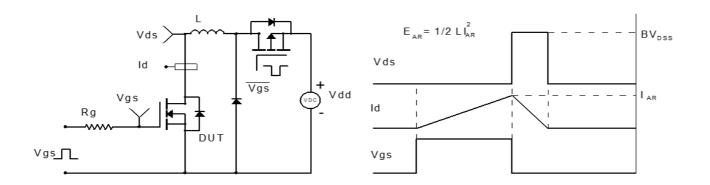


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

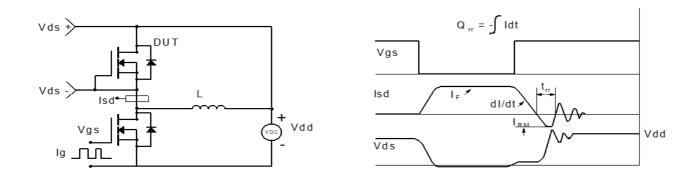
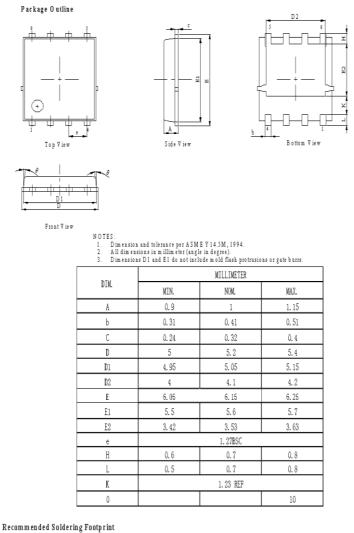


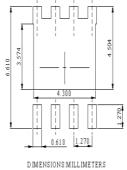
Figure 4: Diode Recovery Test Circuit & Waveform



Package Mechanical Data(PDFN5X6-8L)



kecommended Soldering Footprint



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